National Semiconductor

March 1993

54ACT/74ACT534
Octal D Flip-Flop with TRI-STATE® Outputs

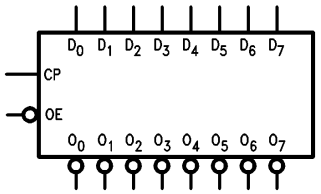
General Description

The 'ACT534 is a high-speed, low-power octal D-type flip-flop featuring separate D-type inputs for each flip-flop and TRI-STATE outputs for bus-oriented applications. A buffered Clock (CP) and Output Enable ($\overline{OE}$) are common to all flip-flops. The 'ACT534 is the same as the 'ACT374 except that the outputs are inverted.

Features

- I_{CC} and I_{OZ} reduced by 50%
- Edge-triggered D-type inputs
- Buffered positive edge-triggered clock
- TRI-STATE outputs for bus-oriented applications
- Outputs source/sink 24 mA
- 'ACT534 has TTL-compatible inputs
- Inverted output version of 'ACT374

Logic Symbols



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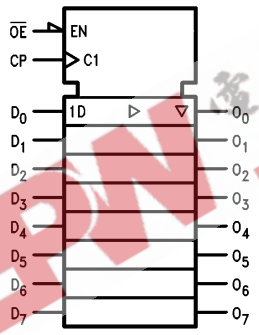
IEEE/IEC



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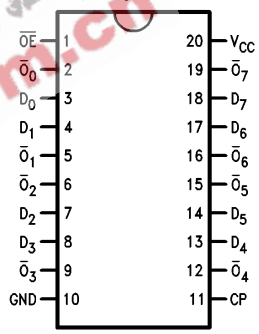
Connection Diagrams

Pin Assignment for DIP, Flatpak and SOIC



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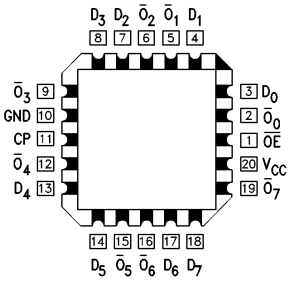
Pin Names	Description
D_0–D_7	Data Inputs
CP	Clock Pulse Input
$\overline{OE}$	TRI-STATE Output Enable Input
$\overline{O}_0$–$\overline{O}_7$	Complementary TRI-STATE Outputs

Pin Assignment for LCC



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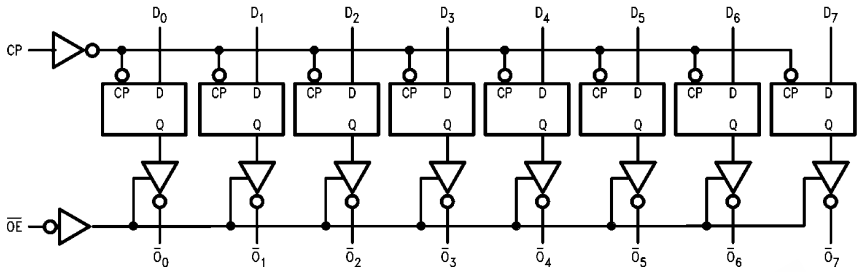
RRD-B30M75/Printed in U. S. A.

Functional Description

The 'ACT534 consists of eight edge-triggered flip-flops with individual D-type inputs and TRI-STATE complementary outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D inputs that meet the setup and hold times requirements on the LOW-to-HIGH Clock (CP) transition. With the Output Enable ($\overline{OE}$) LOW, the contents of the eight flip-flops are available at the outputs. When the $\overline{OE}$ is HIGH, the outputs go to the high impedance state. Operation of the $\overline{OE}$ input does not affect the state of the flip-flops.

Logic Diagram



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Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Function Table

Inputs			Output
CP	**OE**	**D**	$\overline{O}$
⌐‾	L	H	L
⌐‾	L	L	H
L	L	X	$\overline{O}_0$
X	H	X	Z

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
⌐‾ = LOW-to-HIGH Clock Transition
Z = High Impedance
$\overline{O}_0$ = Value stored from previous clock cycle

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	−0.5V to +7.0V
DC Input Diode Current (I_{IK})	
V_I = −0.5V	−20 mA
V_I = V_{CC} + 0.5V	+20 mA
DC Input Voltage (V_I)	−0.5V to V_{CC} + 0.5V
DC Output Diode Current (I_{OK})	
V_O = −0.5V	−20 mA
V_O = V_{CC} + 0.5V	+20 mA
DC Output Voltage (V_O)	−0.5V to V_{CC} + 0.5V
DC Output Source or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	±50 mA
Storage Temperature (T_{STG})	−65°C to +150°C
Junction Temperature (T_J)	
CDIP	175°C
PDIP	140°C

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

Recommended Operating Conditions

Supply Voltage (V_{CC})	
'ACT	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	
74ACT	−40°C to +85°C
54ACT	−55°C to +125°C
Minimum Input Edge Rate (ΔV/Δt)	
'ACT Devices	
V_{IN} from 0.8V to 2.0V	
V_{CC} @ 4.5V, 5.5V	125 mV/ns

DC Characteristics for 'ACT Family Devices

Symbol	Parameter	V_{CC} (V)	74ACT T_A = +25°C	54ACT T_A = −55°C to +125°C	74ACT T_A = −40°C to +85°C	Units	Conditions
			Typ	Guaranteed Limits			
V_{IH}	Minimum High Level Input Voltage	4.5	1.5	2.0	2.0	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
		5.5	1.5	2.0	2.0		
V_{IL}	Maximum Low Level Input Voltage	4.5	1.5	0.8	0.8	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
		5.5	1.5	0.8	0.8		
V_{OH}	Minimum High Level Output Voltage	4.5	4.49	4.4	4.4	V	I_{OUT} = −50 μA
		5.5	5.49	5.4	5.4		
		4.5		3.86	3.70	3.76	V	*V_{IN} = V_{IL} or V_{IH}
		5.5		4.86	4.70	4.76		I_{OH} −24 mA
V_{OL}	Maximum Low Level Output Voltage	4.5	0.001	0.1	0.1	0.1	V	I_{OUT} = 50 μA
		5.5	0.001	0.1	0.1	0.1		
		4.5		0.36	0.50	0.44	V	*V_{IN} = V_{IL} or V_{IH}
		5.5		0.36	0.50	0.44		I_{OL} 24 mA
I_{IN}	Maximum Input Leakage Current	5.5		±0.1	±1.0	±1.0	μA	V_I = V_{CC}, GND
I_{OZ}	Maximum TRI-STATE® Current	5.5		±0.25	±5.0	±2.5	μA	V_I = V_{IL}, V_{IH} V_O = V_{CC}, GND
I_{CCT}	Maximum I_{CC}/Input	5.5	0.6		1.6	1.5	mA	V_I = V_{CC} − 2.1V

*All outputs loaded; thresholds on input associated with output under test.

DC Characteristics for 'ACT Family Devices (Continued)

Symbol	Parameter	V_{CC} (V)	74ACT $T_A = +25°C$		54ACT $T_A = -55°C$ to $+125°C$	74ACT $T_A = -40°C$ to $+85°C$	Units	Conditions
			Typ	Guaranteed Limits				
I_{OLD}	†Minimum Dynamic Output Current	5.5			50	75	mA	V_{OLD} = 1.65V Max
I_{OHD}		5.5			−50	−75	mA	V_{OHD} = 3.85V Min
I_{CC}	Maximum Quiescent Supply Current	5.5		4.0	80.0	40.0	μA	$V_{IN} = V_{CC}$ or GND

†Maximum test duration 2.0 ms, one output loaded at a time.

Note: I_{CC} for 54ACT @ 25°C is identical to 74ACT @ 25°C.

AC Electrical Characteristics

Symbol	Parameter	V_{CC}* (V)	74ACT $T_A = +25°C$, $C_L = 50$ pF			54ACT $T_A = -55°C$ to $+125°C$, $C_L = 50$ pF		74ACT $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF		Units
			Min	Typ	Max	Min	Max	Min	Max	
f_{max}	Maximum Clock Frequency	5.0		100		85		120		MHz
t_{PLH}	Propagation Delay CP to $\overline{Q}_n$	5.0	2.5	6.5	11.5	1.5	14.0	2.0	12.5	ns
t_{PHL}	Propagation Delay CP to $\overline{Q}_n$	5.0	2.0	6.0	10.5	1.5	13.0	2.0	12.0	ns
t_{PZH}	Output Enable Time	5.0	2.5	6.5	12.0	1.5	14.0	2.0	12.5	ns
t_{PZL}	Output Enable Time	5.0	2.0	6.0	11.0	1.5	13.0	2.0	11.5	ns
t_{PHZ}	Output Disable Time	5.0	1.5	7.0	12.5	1.5	14.5	1.0	13.5	ns
t_{PLZ}	Output Disable Time	5.0	1.5	5.5	10.5	1.5	11.5	1.0	10.5	ns

*Voltage Range 5.0 is 5.0V ±0.5V

AC Operating Requirements

Symbol	Parameter	V_{CC}* (V)	74ACT $T_A = +25°C$, $C_L = 50$ pF		54ACT $T_A = -55°C$ to $+125°C$, $C_L = 50$ pF	74ACT $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF	Units
			Typ	Guaranteed Minimum			
t_s	Setup Time, HIGH or LOW D_n to CP	5.0	1.0	3.5	5.0	4.0	ns
t_h	Hold Time, HIGH or LOW D_n to CP	5.0	−1.0	1.0	3.0	1.5	ns
t_w	CP Pulse Width HIGH or LOW	5.0	2.0	3.5	5.0	3.5	ns

*Voltage Range 5.0 is 5.0V ±0.5V

Capacitance

Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	4.5	pF	V_{CC} = OPEN
C_{PD}	Power Dissipation Capacitance	40.0	pF	V_{CC} = 5.0V

Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:

74ACT 534 P C QR

Temperature Range Family
- 74ACT = Commercial TTL-Compatible
- 54ACT = Military TTL-Compatible

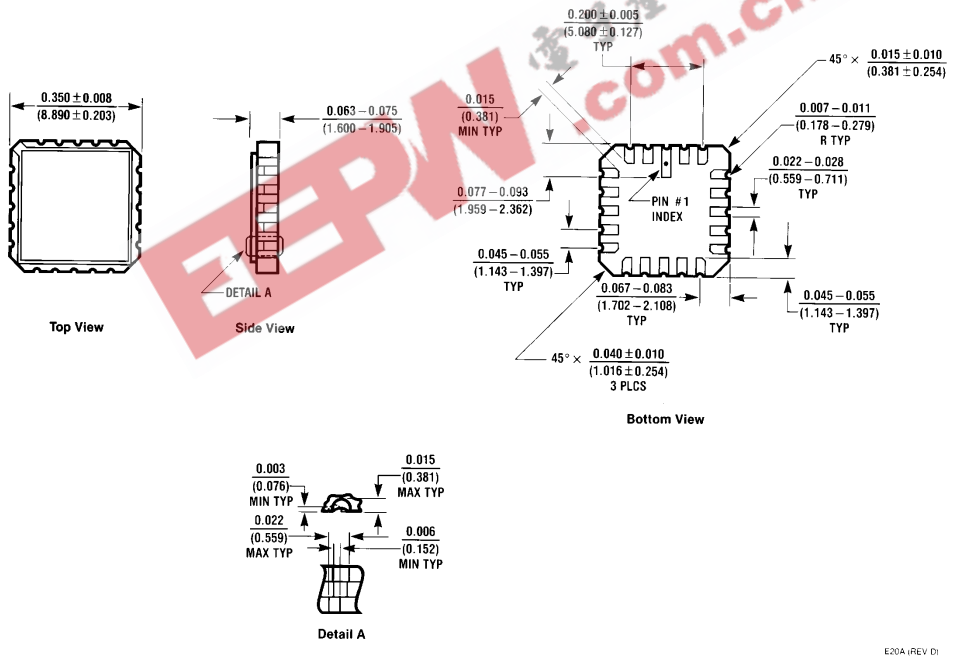
Device Type

Package Code
- P = Plastic DIP
- D = Ceramic DIP
- F = Flatpak
- L = Leadless Ceramic Chip Carrier (LCC)
- S = Small Outline (SOIC)

Special Variations
- X = Devices shipped in 13″ reels
- QR = Commercial grade device with burn-in
- QB = Military grade device with environmental and burn-in processing shipped in tubes

Temperature Range
- C = Commercial (−40°C to +85°C)
- M = Military (−55°C to +125°C)

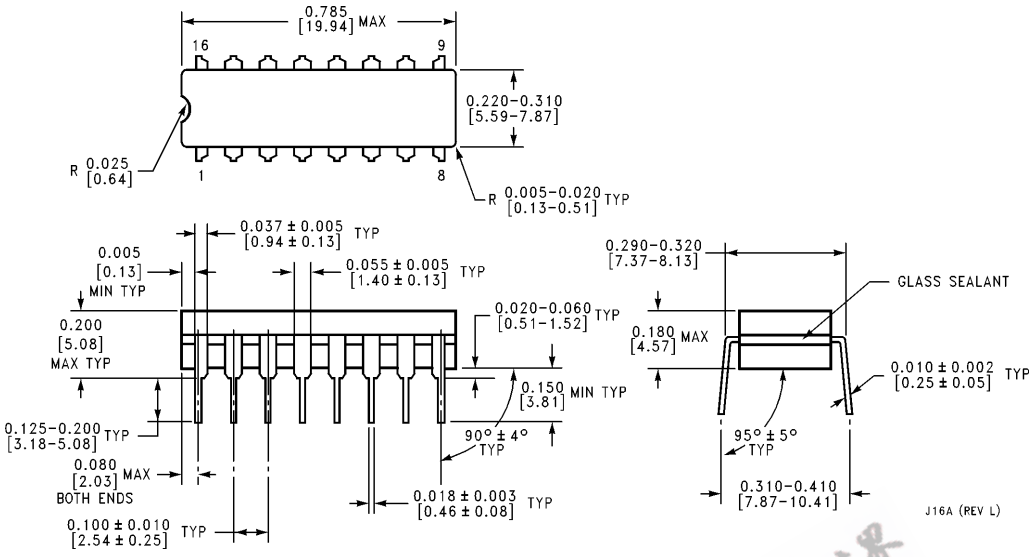
Physical Dimensions inches (millimeters)



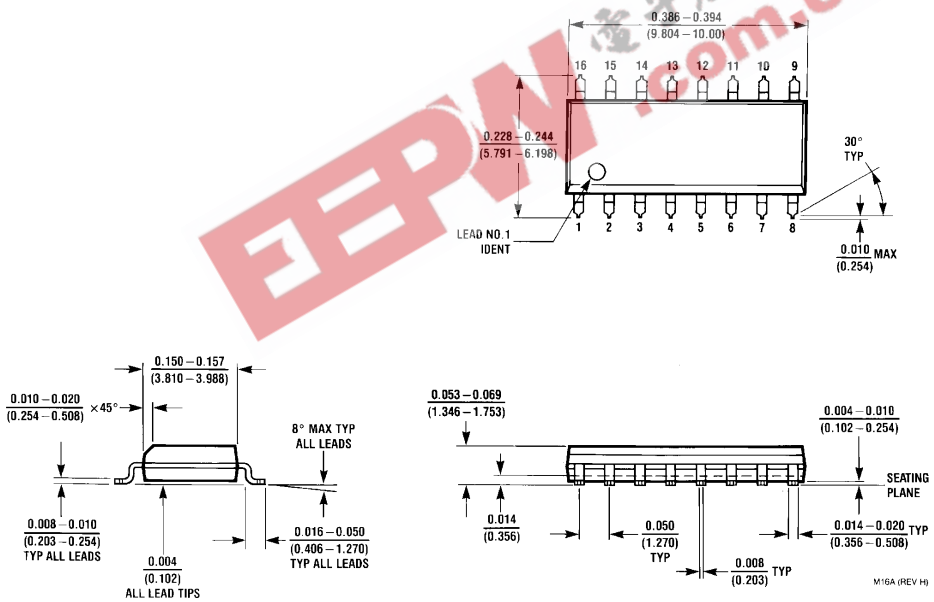
E20A (REV D)

20 Terminal Ceramic Leadless Chip Carrier (L)
NS Package Number E20A

Physical Dimensions inches (millimeters) (Continued)

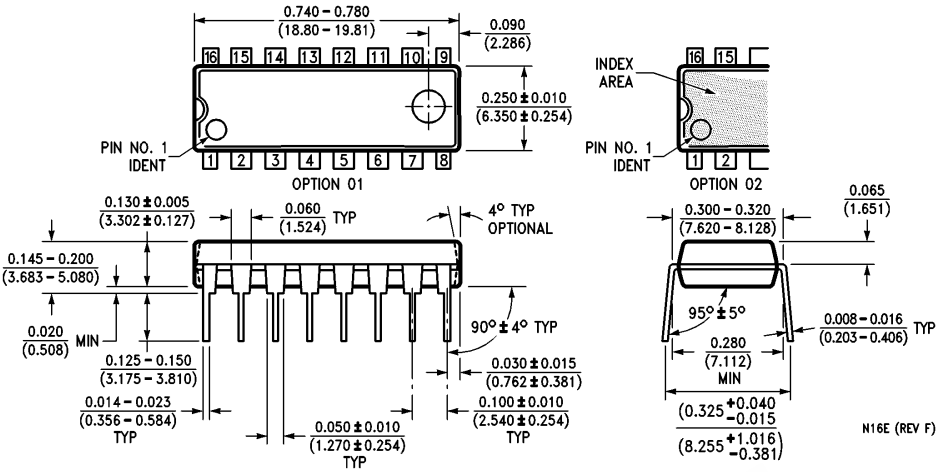


16 Lead Ceramic Dual-In-Line Package (D)
NS Package Number J16A



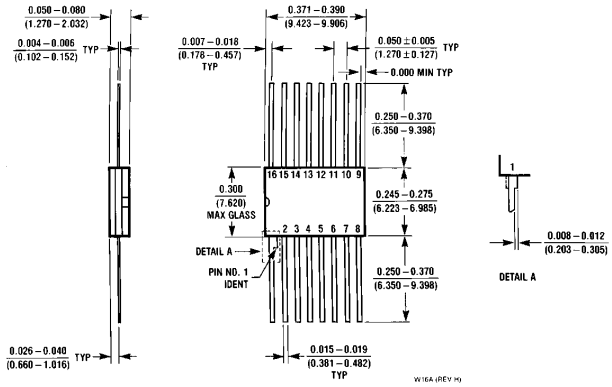
16 Lead Small Outline Integrated Circuit (S)
NS Package Number M16A

Physical Dimensions inches (millimeters) (Continued)



16 Lead Plastic Dual-In-Line Package (P)
NS Package Number N16E

Physical Dimensions inches (millimeters) (Continued)



16 Lead Ceramic Flatpak (F)
NS Package Number W16A

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